


<b>Search Notes</b>  	<b>Application/Control No.</b>  10581752	<b>Applicant(s)/Patent Under Reexamination</b>  DEORE ET AL.
	<b>Examiner</b>  SHANE FANG	<b>Art Unit</b>  1766

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
528	422	12/14/2009	sf

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
NPL and STIC searched	12/14/2009	sf
search updated	8/9/2010	sf
search updated	3/28/2011	sf
search updated	1/4/2012	sf

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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